



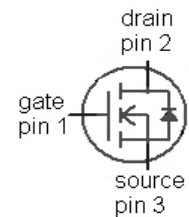
**OptiMOS® Power-Transistor**
**Features**

- For fast switching converters and sync. rectification
- N-channel enhancement - normal level
- 175 °C operating temperature
- Avalanche rated
- Pb-free lead plating, RoHS compliant

**Product Summary**

|                             |     |    |
|-----------------------------|-----|----|
| $V_{DS}$                    | 60  | V  |
| $R_{DS(on),max}$ SMDversion | 4.7 | mΩ |
| $I_D$                       | 100 | A  |

| Type           | IPP050N06L   | IPB050N06L   |
|----------------|--|--|
|                |  |  |
| <b>Package</b> | P-TO220-3-1  | P-TO263-3-2  |
| <b>Marking</b> | 050N06L  | 050N06L  |


**Maximum ratings, at  $T_j=25\text{ °C}$ , unless otherwise specified**

| Parameter                           | Symbol         | Conditions  | Value       | Unit              |
|-------------------------------------|----------------|---|-------------|-------------------|
| Continuous drain current            | $I_D$          | $T_C=25\text{ °C}^{1)}$   | 100         | A                 |
|                                     |                | $T_C=100\text{ °C}$   | 100         |                   |
| Pulsed drain current                | $I_{D,pulse}$  | $T_C=25\text{ °C}^{2)}$   | 400         |                   |
| Avalanche energy, single pulse      | $E_{AS}$       | $I_D=100\text{ A}, R_{GS}=25\text{ }\Omega$   | 810         | mJ                |
| Reverse diode $dv/dt$               | $dv/dt$        | $I_D=100\text{ A}, V_{DS}=48\text{ V},$<br>$di/dt=200\text{ A}/\mu\text{s},$<br>$T_{j,max}=175\text{ °C}$ | 6           | kV/ $\mu\text{s}$ |
| Gate source voltage                 | $V_{GS}$       |   | $\pm 20$    | V                 |
| Power dissipation                   | $P_{tot}$      | $T_C=25\text{ °C}$  | 300         | W                 |
| Operating and storage temperature   | $T_j, T_{stg}$ |   | -55 ... 175 | °C                |
| IEC climatic category; DIN IEC 68-1 |                |   | 55/175/56   |                   |

<sup>1)</sup> Current is limited by bondwire; with an  $R_{thJC}=0.5$  the chip is able to carry 160A

<sup>2)</sup> See figure 3

| Parameter | Symbol | Conditions | Values |      |      | Unit |
|-----------|--------|------------|--------|------|------|------|
|           |        |            | min.   | typ. | max. |      |

**Thermal characteristics**

|                                     |            |  |   |   |     |     |
|-------------------------------------|------------|--|---|---|-----|-----|
| Thermal resistance, junction - case | $R_{thJC}$ |  | - | - | 0.5 | K/W |
| SMD version, device on PCB          | $R_{thJA}$ | minimal footprint                            | - | - | 62  |     |
|                                     |            | 6 cm <sup>2</sup> cooling area <sup>3)</sup> | - | - | 40  |     |

**Electrical characteristics, at  $T_j=25\text{ °C}$ , unless otherwise specified**
**Static characteristics**

|                                  |               |  |     |      |     |               |
|----------------------------------|---------------|--|-----|------|-----|---------------|
| Drain-source breakdown voltage   | $V_{(BR)DSS}$ | $V_{GS}=0\text{ V}, I_D=1\text{ mA}$                       | 60  | -    | -   | V             |
| Gate threshold voltage           | $V_{GS(th)}$  | $V_{DS}=V_{GS}, I_D=270\text{ }\mu\text{A}$                | 2.1 | 3    | 4   |               |
| Zero gate voltage drain current  | $I_{DSS}$     | $V_{DS}=60\text{ V}, V_{GS}=0\text{ V}, T_j=25\text{ °C}$  | -   | 0.01 | 1   | $\mu\text{A}$ |
|                                  |               | $V_{DS}=60\text{ V}, V_{GS}=0\text{ V}, T_j=125\text{ °C}$ | -   | 1    | 100 |               |
| Gate-source leakage current      | $I_{GSS}$     | $V_{GS}=20\text{ V}, V_{DS}=0\text{ V}$                    | -   | 10   | 100 | nA            |
| Drain-source on-state resistance | $R_{DS(on)}$  | $V_{GS}=10\text{ V}, I_D=100\text{ A}$                     | -   | 4.1  | 5   | m $\Omega$    |
|                                  |               | $V_{GS}=10\text{ V}, I_D=100\text{ A},$<br>SMD version     |     | 3.8  | 4.7 |               |
| Gate resistance                  | $R_G$         |  | -   | 1.9  | -   | $\Omega$      |
| Transconductance                 | $g_{fs}$      | $ V_{DS} >2 I_D R_{DS(on)max},$<br>$I_D=100\text{ A}$      | 74  | 148  | -   | S             |

<sup>3)</sup> Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm<sup>2</sup> (one layer, 70  $\mu\text{m}$  thick) copper area for drain connection. PCB is vertical in still air.

| Parameter | Symbol | Conditions | Values |      |      | Unit |
|-----------|--------|------------|--------|------|------|------|
|           |        |            | min.   | typ. | max. |      |

**Dynamic characteristics**

|                              |              |  |   |      |      |    |
|------------------------------|--------------|--|---|------|------|----|
| Input capacitance            | $C_{iss}$    | $V_{GS}=0\text{ V}, V_{DS}=30\text{ V},$<br>$f=1\text{ MHz}$                     | - | 4600 | 6100 | pF |
| Output capacitance           | $C_{oss}$    |  | - | 1500 | 2000 |    |
| Reverse transfer capacitance | $C_{rss}$    |  | - | 350  | 525  |    |
| Turn-on delay time           | $t_{d(on)}$  | $V_{DD}=30\text{ V}, V_{GS}=10\text{ V},$<br>$I_D=100\text{ A}, R_G=2.2\ \Omega$ | - | 21   | 32   | ns |
| Rise time                    | $t_r$        |  | - | 31   | 47   |    |
| Turn-off delay time          | $t_{d(off)}$ |  | - | 59   | 88   |    |
| Fall time                    | $t_f$        |  | - | 30   | 45   |    |

**Gate Charge Characteristics<sup>4)</sup>**

|                          |               |   |   |     |     |    |
|--------------------------|---------------|---|---|-----|-----|----|
| Gate to source charge    | $Q_{gs}$      | $V_{DD}=30\text{ V}, I_D=100\text{ A},$<br>$V_{GS}=0\text{ to }10\text{ V}$ | - | 24  | 32  | nC |
| Gate charge at threshold | $Q_{g(th)}$   |   | - | 9.7 | 13  |    |
| Gate to drain charge     | $Q_{gd}$      |   | - | 51  | 76  |    |
| Switching charge         | $Q_{sw}$      |   | - | 65  | 95  |    |
| Gate charge total        | $Q_g$         |   | - | 126 | 167 |    |
| Gate plateau voltage     | $V_{plateau}$ |   | - | 5.2 | -   | V  |
| Output charge            | $Q_{oss}$     | $V_{DD}=30\text{ V}, V_{GS}=0\text{ V}$                                     | - | 47  | 62  |    |

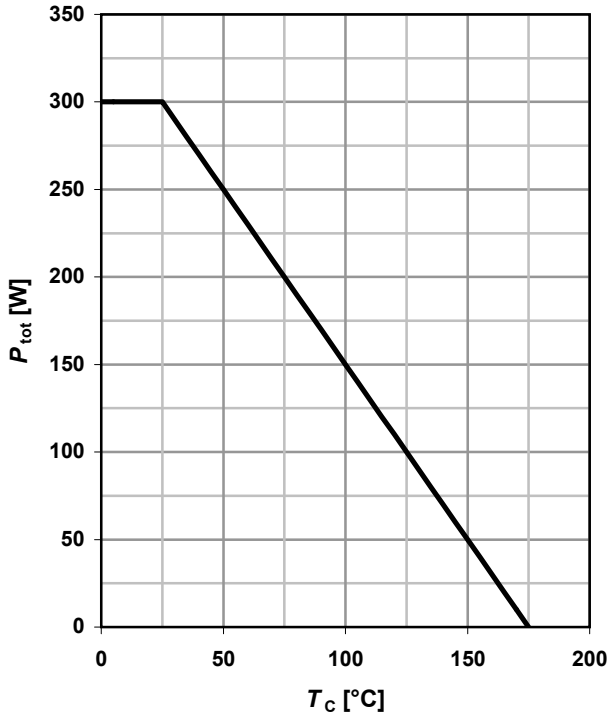
**Reverse Diode**

|                                  |               |  |   |      |     |    |
|----------------------------------|---------------|--|---|------|-----|----|
| Diode continuous forward current | $I_S$         | $T_C=25\text{ }^\circ\text{C}$   | - | -    | 100 | A  |
| Diode pulse current              | $I_{S,pulse}$ |  | - | -    | 400 |    |
| Diode forward voltage            | $V_{SD}$      | $V_{GS}=0\text{ V}, I_F=100\text{ A},$<br>$T_J=25\text{ }^\circ\text{C}$ | - | 0.93 | 1.3 | V  |
| Reverse recovery time            | $t_{rr}$      | $V_R=30\text{ V}, I_F=I_S,$<br>$di_F/dt=100\text{ A}/\mu\text{s}$        | - | 60   | 75  | ns |
| Reverse recovery charge          | $Q_{rr}$      |  | - | 130  | 160 | nC |

<sup>4)</sup> See figure 16 for gate charge parameter definition

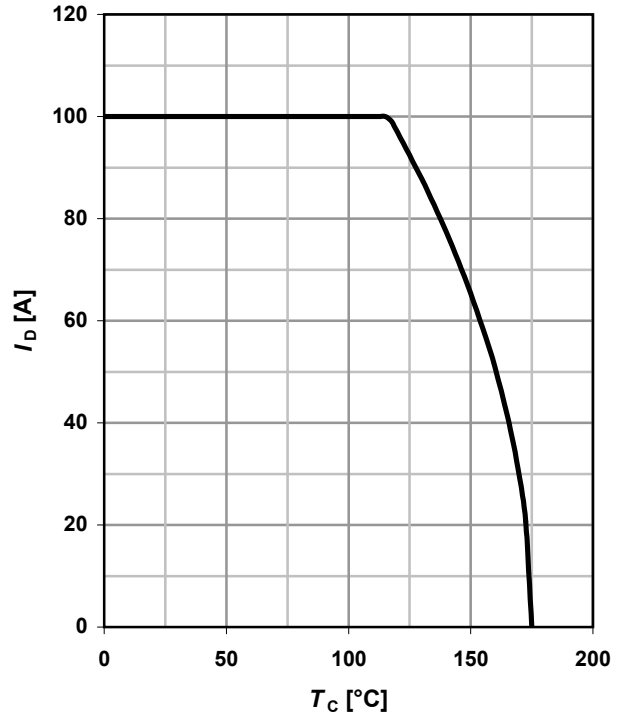
**1 Power dissipation**

$P_{tot}=f(T_C); V_{GS} \geq 6 \text{ V}$



**2 Drain current**

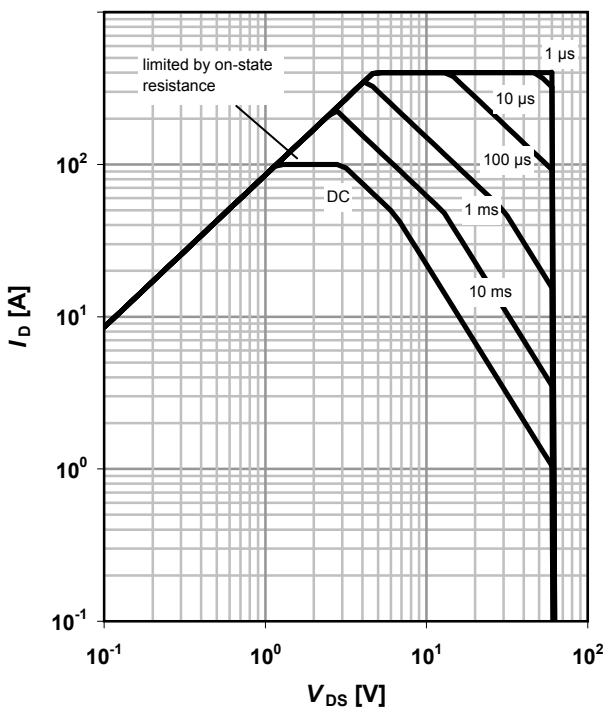
$I_D=f(T_C); V_{GS} \geq 10 \text{ V}$



**3 Safe operating area**

$I_D=f(V_{DS}); T_C=25 \text{ °C}; D=0$

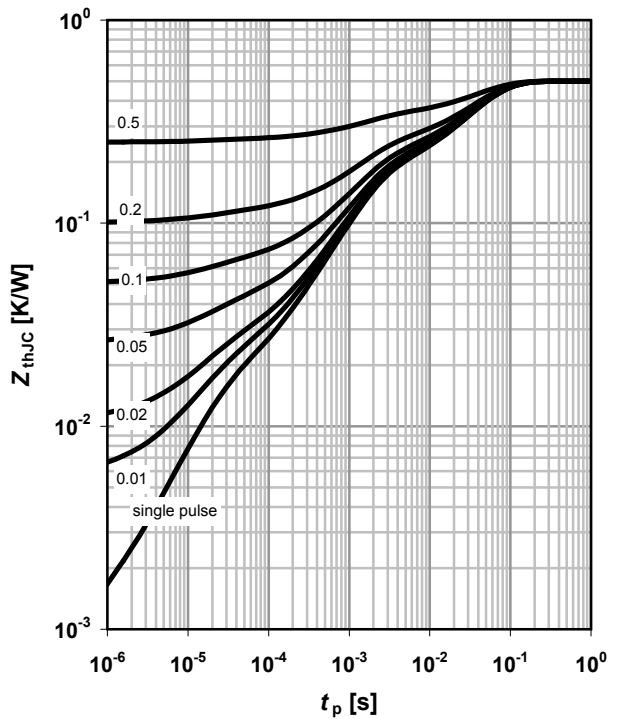
parameter:  $t_p$



**4 Max. transient thermal impedance**

$Z_{thJC}=f(t_p)$

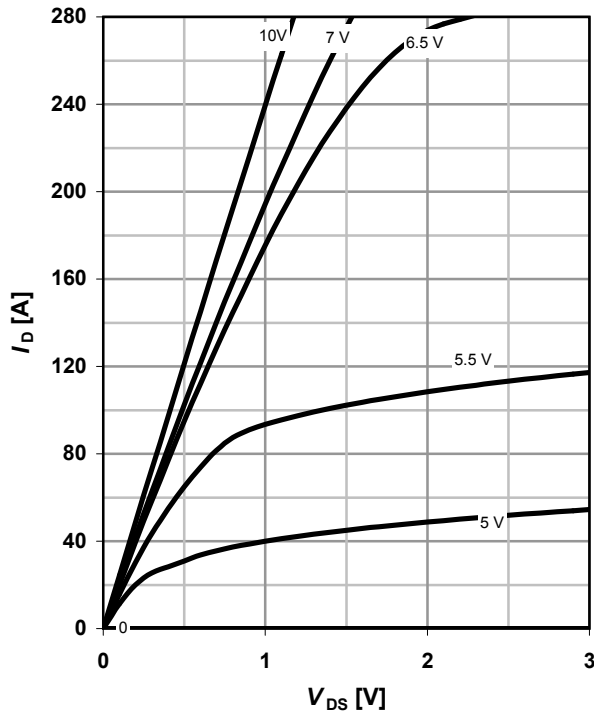
parameter:  $D=t_p/T$



**5 Typ. output characteristics**

$I_D = f(V_{DS}); T_j = 25\text{ }^\circ\text{C}$

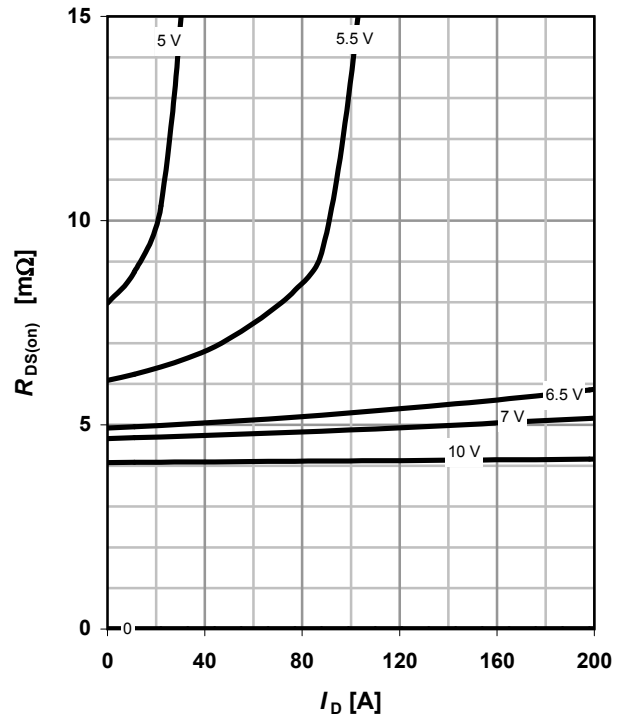
parameter:  $V_{GS}$



**6 Typ. drain-source on resistance**

$R_{DS(on)} = f(I_D); T_j = 25\text{ }^\circ\text{C}$

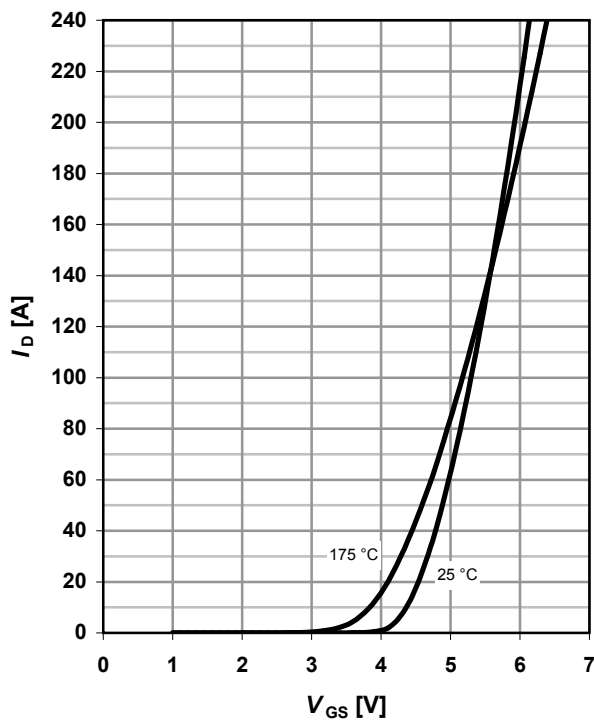
parameter:  $V_{GS}$



**7 Typ. transfer characteristics**

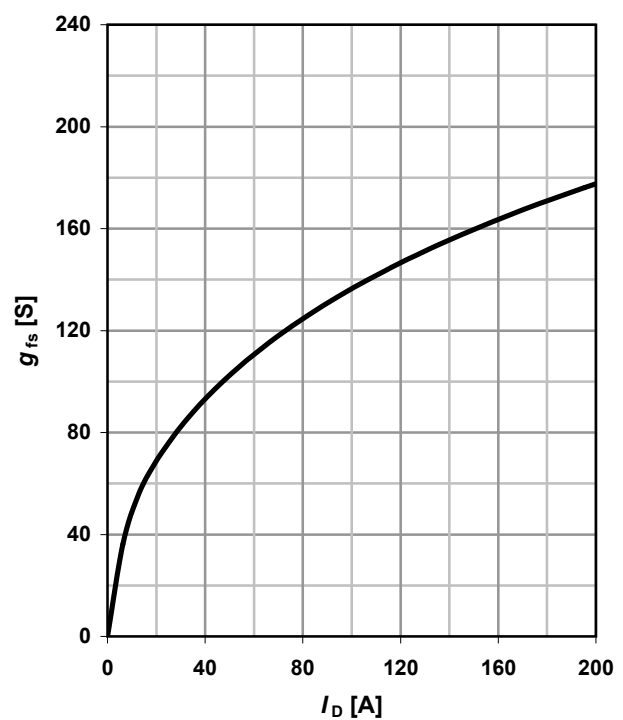
$I_D = f(V_{GS}); |V_{DS}| > 2|I_D|R_{DS(on)max}$

parameter:  $T_j$



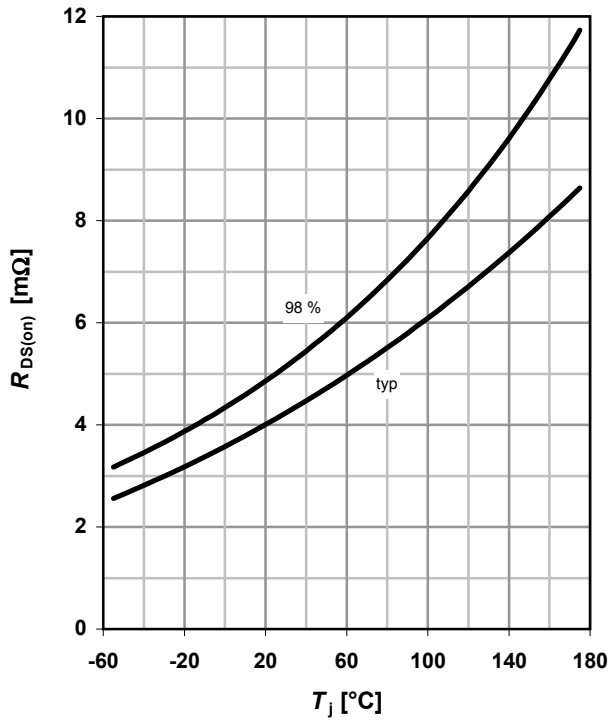
**8 Typ. forward transconductance**

$g_{fs} = f(I_D); T_j = 25\text{ }^\circ\text{C}$



**9 Drain-source on-state resistance**

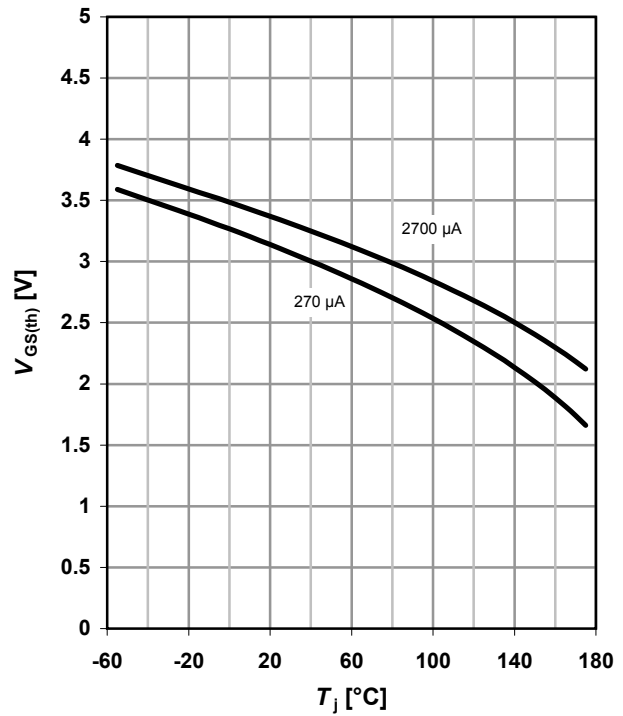
$R_{DS(on)}=f(T_j); I_D=100\text{ A}; V_{GS}=10\text{ V}$



**10 Typ. gate threshold voltage**

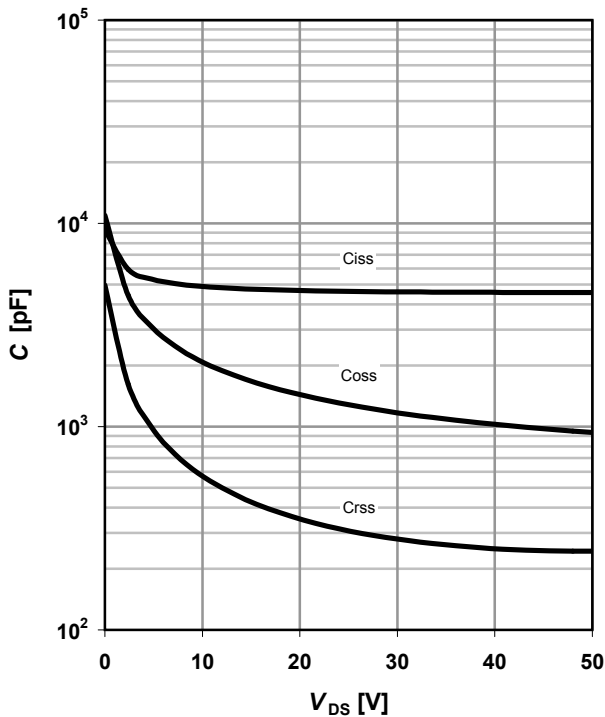
$V_{GS(th)}=f(T_j); V_{GS}=V_{DS}$

parameter:  $I_D$



**11 Typ. capacitances**

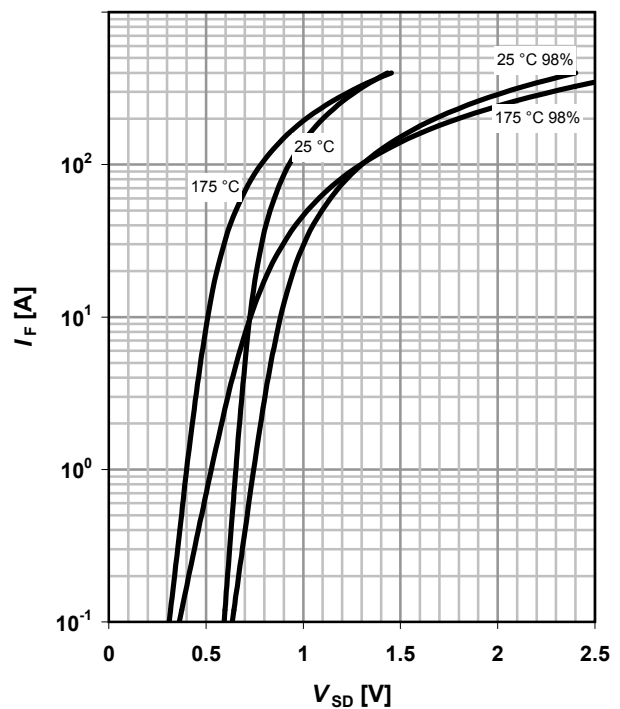
$C=f(V_{DS}); V_{GS}=0\text{ V}; f=1\text{ MHz}$



**12 Forward characteristics of reverse diode**

$I_F=f(V_{SD})$

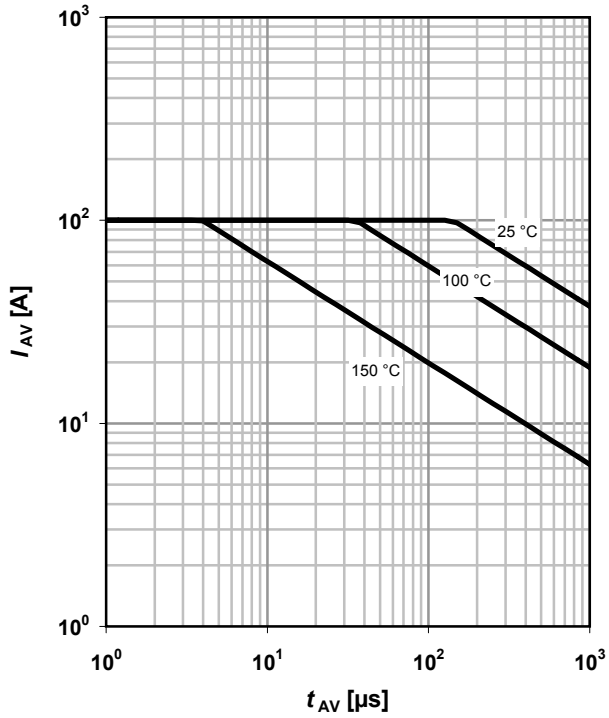
parameter:  $T_j$



**13 Avalanche characteristics**

$I_{AS}=f(t_{AV}); R_{GS}=25 \Omega$

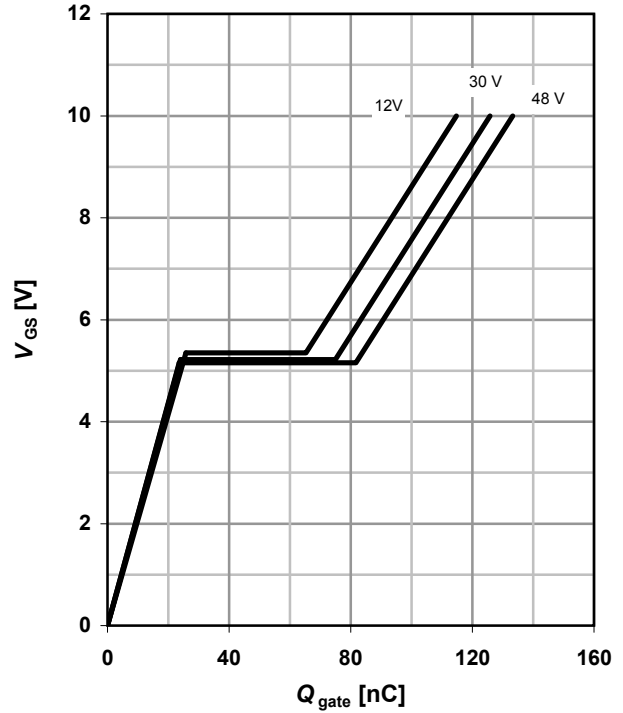
parameter:  $T_{j(\text{start})}$



**14 Typ. gate charge**

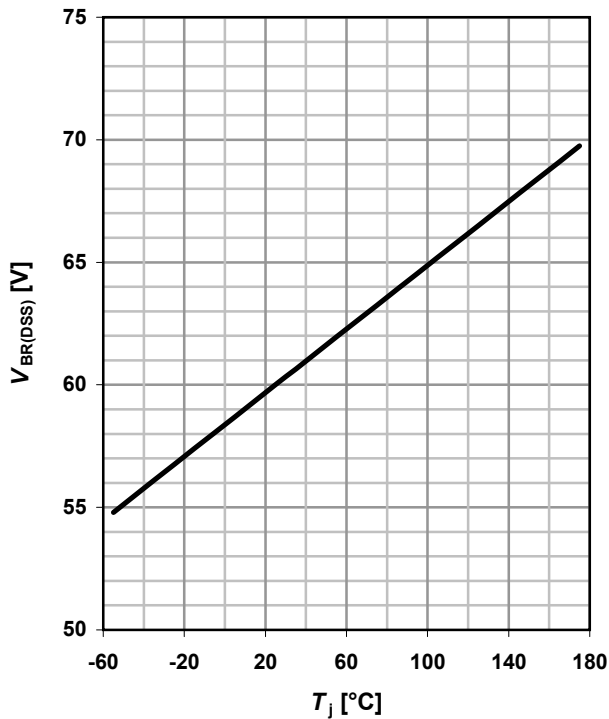
$V_{GS}=f(Q_{\text{gate}}); I_D=100 \text{ A pulsed}$

parameter:  $V_{DD}$

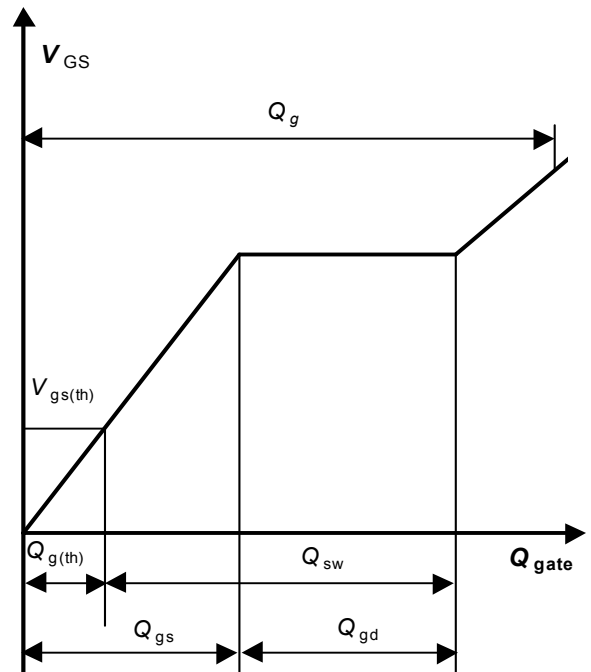


**15 Drain-source breakdown voltage**

$V_{BR(DSS)}=f(T_j); I_D=1 \text{ mA}$



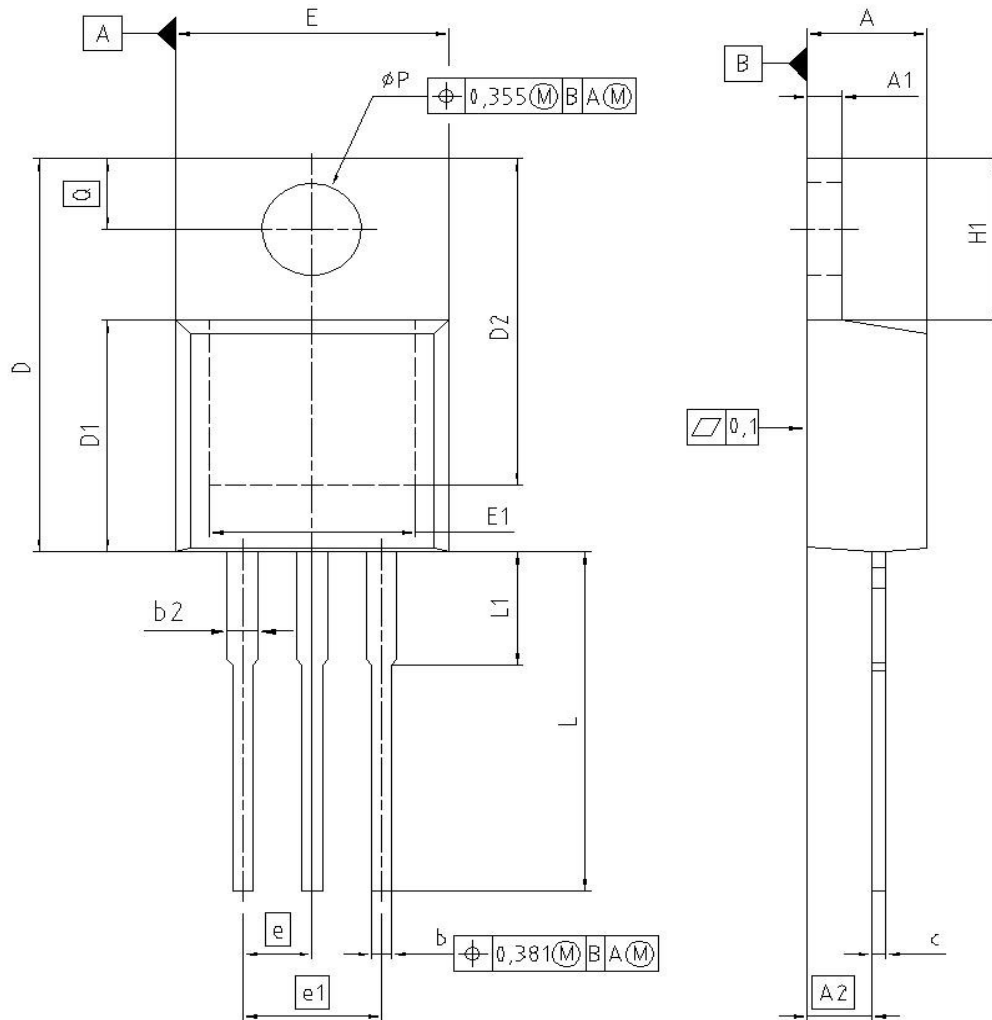
**16 Gate charge waveforms**







PG-TO220-3: Outline



| DIM | MILLIMETERS |        | INCHES |       |
|-----|-------------|--------|--------|-------|
|     | MIN         | MAX    | MIN    | MAX   |
| A   | 4.300       | 4.572  | 0.169  | 0.180 |
| A1  | 1.170       | 1.400  | 0.046  | 0.055 |
| A2  | 2.215       | 2.718  | 0.087  | 0.107 |
| b   | 0.650       | 0.864  | 0.026  | 0.034 |
| b2  | 0.635       | 1.778  | 0.025  | 0.070 |
| c   | 0.330       | 0.600  | 0.013  | 0.024 |
| D   | 14.808      | 15.950 | 0.583  | 0.628 |
| D1  | 8.509       | 9.450  | 0.335  | 0.372 |
| D2  | 12.850      | 13.100 | 0.506  | 0.516 |
| E   | 9.700       | 10.363 | 0.382  | 0.408 |
| E1  | 6.500       | 8.600  | 0.256  | 0.339 |
| e   | 2.540       |        | 0.100  |       |
| e1  | 5.080       |        | 0.200  |       |
| N   | 3           |        | 3      |       |
| H1  | 5.900       | 6.900  | 0.232  | 0.272 |
| L   | 13.000      | 14.000 | 0.512  | 0.551 |
| L1  | -           | 4.800  | -      | 0.189 |
| pP  | 3.700       | 3.886  | 0.146  | 0.153 |
| Q   | 2.600       | 3.000  | 0.102  | 0.118 |

REFERENCE  
JEDEC TO220

SCALE

EUROPEAN PROJECTION

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